Silicon N-channel IGBT 1700V F version

#### 1.FEATURES

- \* Soft switching behavior & low conduction loss:
  - Soft low-injection punch-through with trench gate IGBT.
- \* Low driving power:

Low input capacitance with advanced trench gate.

\* Low noise recovery: Ultra soft fast recovery diode.

#### 2.ABSOLUTE MAXIMUM RATINGS (TC=25°C)

Item		Symbol	Unit	MBL1200E17F
Collector Emitter Voltage		Vces	V	1,700
Gate Emitter Voltage		VGES	V	±20
Callanton Commant	DC	Ic	Λ	1,200
Collector Current	1ms	ICp	Α	2,400
Forward Current	DC	IF(FWD)	A	1,200
(Free wheel Diode	e) 1ms	IFM(FWD)		2,400
Forward Current	DC	IF(chopper)	Α	1,200
(Chopper Diode)	1ms	IFM(chopper)		2,400
Junction Temperature		Tj	°C	-50 ~ <b>+</b> 150
Storage Temperature		Tstg	°C	-55 ~ +125
Isolation Test Voltage		Viso	VRMS	6,000(AC 1 minute)
Screw Torque	Terminals (M4/M8)	-	N∙m	2/15 (1)
	Mounting (M6)	-		6 (2)

Notes: (1) Recommended Value  $1.8\pm0.2$  /  $15^{+0}$ /- $_3$ N·m

(2) Recommended Value 5.5±0.5N·m

### 3.ELECTRICAL CHARACTERISTICS

Item	Symbol	Unit	Min.	Тур.	Max.	Test Conditions	
Callanta - Fraitta - Cut Off Current	loso	mA	-	-	10	VCE=1,700V, VGE=0V, Tj=25°C	
Collector Emitter Cut-Off Current	ICES		-	23	-	Vce=1,700V, Vge=0V, Tj=150°C	
Gate Emitter Leakage Current	IGES	nA	-500	-	+500	VGE=±20V, VCE=0V, Tj=25°C	
Collector Emitter Seturation Voltage	V(0F(+)	V	-	2.0	-	Ic=1,200A, V <sub>GE</sub> =15V, Tj=25°C	
Collector Emitter Saturation Voltage	VCE(sat)		-	2.4	-	I <sub>C</sub> =1,200A, V <sub>GE</sub> =15V, Tj=150°C	
Gate Emitter Threshold Voltage	VGE(TO)	V	4.1	5.5	7.1	V <sub>CE</sub> =10V, I <sub>C</sub> =120mA, Tj=25°C	
nput Capacitance	Cies	nF	-	63	-	V <sub>CE</sub> =10V, V <sub>GE</sub> =0V, f=100kHz, Tj=25°C	
Internal Gate Resistance	Rge	Ω	-	4	-	V <sub>CE</sub> =10V, V <sub>GE</sub> =0V, f=100kHz, Tj=25°C	
Turn On Delay Time	t <sub>d(on)</sub>	t <sub>d(on)</sub>		0.74	1.70	V <sub>CC</sub> =900V, Ic=1,200A,	
Rise Time	t <sub>r</sub>		-	0.26	0.80	L=100nH,	
Turn Off Delay Time	t <sub>d(off)</sub>	μS	-	1.9	3.0	$R_{G}(\text{on/off})=2.7/4.7\Omega \qquad (3)$	
Fall Time	t <sub>f</sub>		-	1.6	3.0	V <sub>GE</sub> =±15V, Tj=150°C	
Turn On Loss	Eon	J/P	-	0.40	0.90		
Turn Off Loss	Eoff	J/P	-	0.93	1.5		
Peak Forward Voltage Drop	VFM	V	-	2.0	-	IF=1,200A, V <sub>GE</sub> =0V, Tj=25°C	
reak rorward voltage brop	V 1 101					Measured at auxiliary terminals	
			-	2.3	-	IF=1,200A, V <sub>GE</sub> =0V, Tj=150°C	
						Measured at auxiliary terminals	
Reverse Recovery Time	t <sub>rr</sub>	μS	-	0.65	1.5	V <sub>CC</sub> =900V, IF=1,200A,	
Reverse Recovery Loss	Err	J/P	-	0.48	1.0	L=100nH, R <sub>G</sub> (on/off)= $2.7/4.7\Omega$ (3) V <sub>GE</sub> = $\pm 15$ V, Tj= $150$ °C	
Thormal Impadance IGBT	Rth(j-c)	K/W	-	-	0.022	Junction to case	
Thermal Impedance FWD	Rth(j-c)	r\/VV	-	-	0.033	Junction to case	
Contact Thermal Impedance	Rth(c-f)	K/W	-	0.016	-	Case to fin (at IGBT+FWD part)	

2) Chopper DIODE

Item	Symbol	Unit	Min.	Тур.	Max.	Test Conditions	
Depatitive Deverse Current	IRRM	mA	-	-	10.0	VR=1,700V, Tj=25°C	
Repetitive Reverse Current	IKKW		-	23	-	VR=1,700V, Tj=150°C	
		V	-	2.1	-	IF=1,200A, Tj=25°C	
Forward Voltage Drop	VF					Measured at main terminal	
(Between main terminals)	VF			2.4		IF=1,200A, Tj=150°C	
						Measured at main terminal	
Reverse Recovery Time	trr	μS	-	0.65	1.5	Vcc=900V, IF=1,200A,	
Poverse Pessyery Less	Err	J/P	-	0.48	1.0	L=100nH, $R_G(on)=2.7\Omega$ (3)	
Reverse Recovery Loss	⊏rr					V <sub>GE</sub> =±15V, Tj=150°C	
Thermal Impedance	Rth(j-c)	K/W			0.033	Junction to case	
Contact Thermal Impedance	Rth(c-f)	K/W	-	0.016	-	Case to fin (at Chopper Diode part)	

Notes: (3) R<sub>G</sub> value is the test condition's value for decision of the switching times, not recommended value. Please, determine the suitable R<sub>G</sub> value after the measurement of switching waveforms(overshoot voltage, etc.)with appliance mounted.

#### 4.Material declaration

Please note the following materials are contained in the product, in order to keep characteristic and reliability level.

Material	Contained part		
Lead (Pb) and its compounds	Solder		

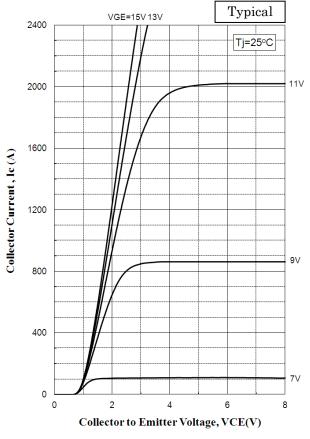
<sup>\*</sup> Please contact our representatives at order.

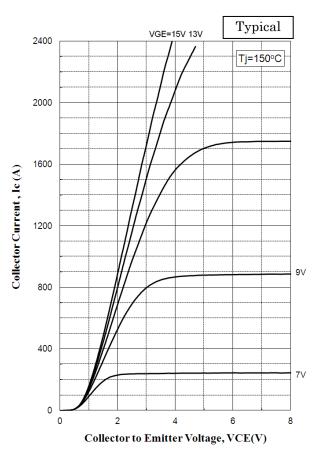
<sup>\*</sup> For improvement, specifications are subject to change without notice.

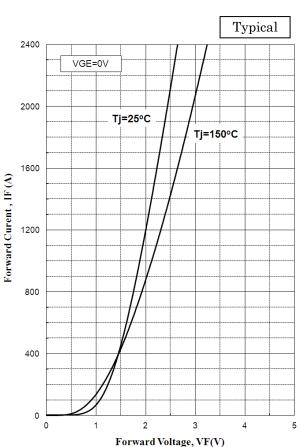
<sup>\*</sup> For actual application, please confirm this spec sheet is the newest revision

<sup>\*</sup> ELECTRICAL CHARACTERISTIC items shown in above table are according to IEC 60747–2 and IEC 60747–9.

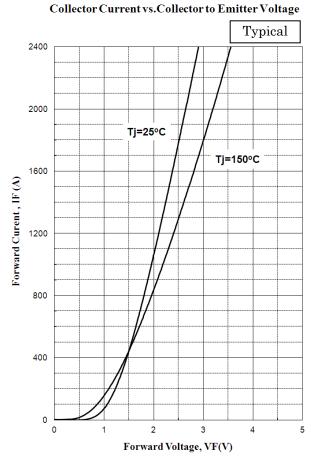
#### 5.CHARACTERISTICS CURVE 5.1 STATIC CHARACTERISTICS





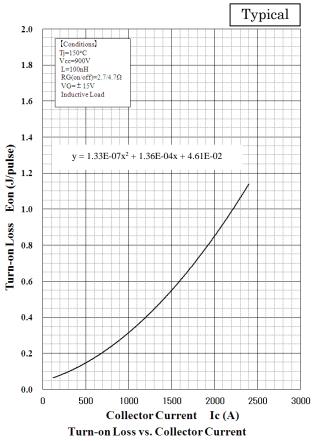


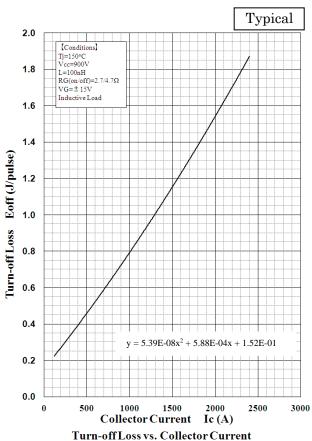
Forward Voltage of free-wheeling diode

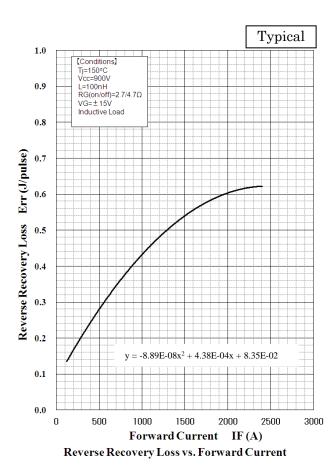


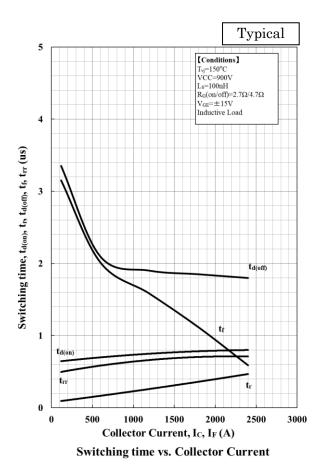
Forward Voltage of Chopper diode

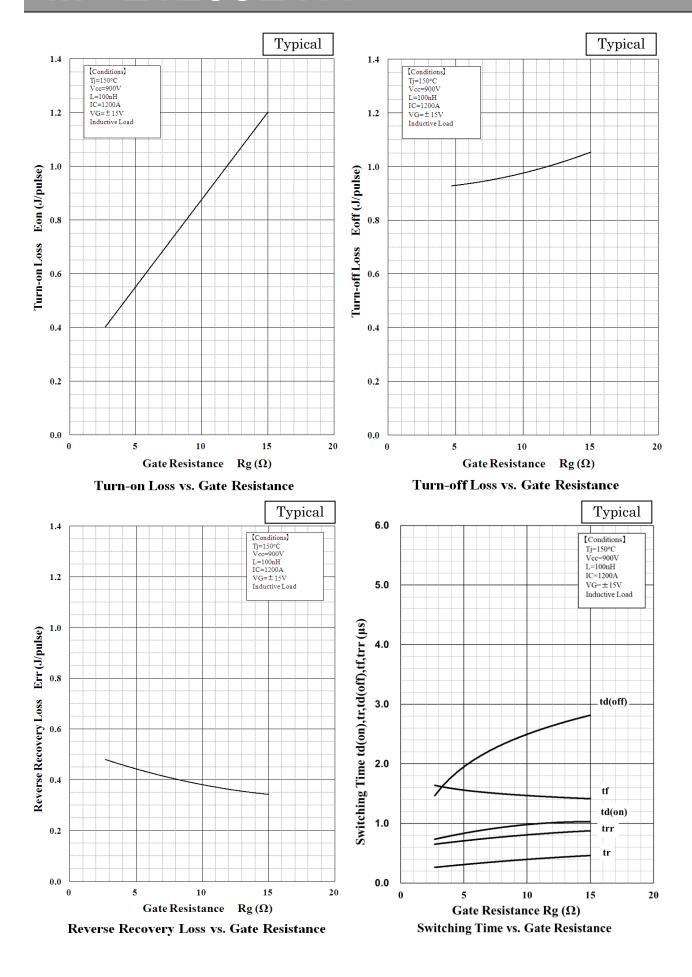
#### **5.2 DYNAMIC CHARACTERISTICS**



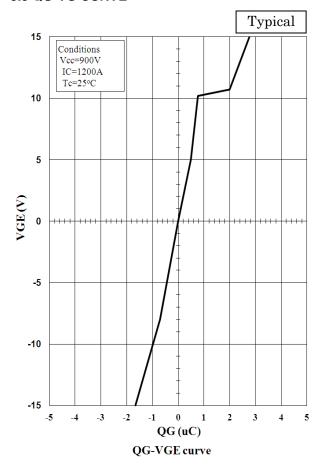




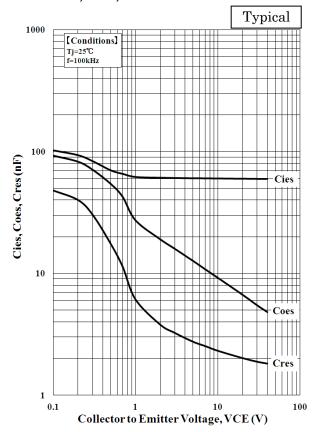




#### 5.3 QG-VG CURVE

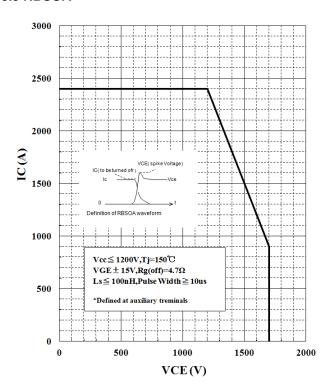


#### 5.4 Cies, Coes, Cres CURVE

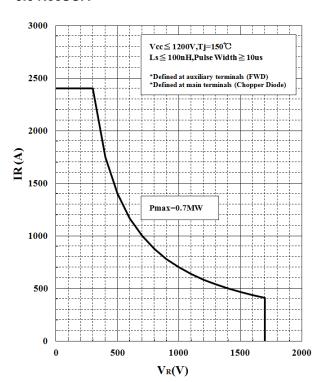


Capacitance vs. Collector to Emitter Voltage

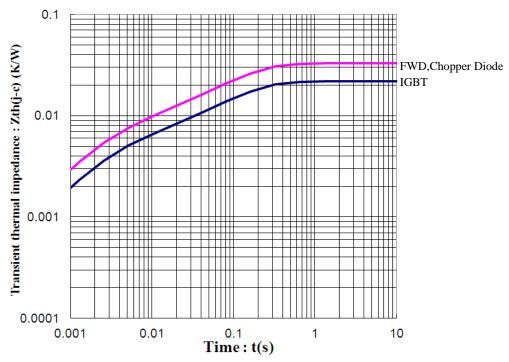
#### 5.5 RBSOA



#### 5.6 RecSOA



#### **6. TRANSIENT THERMAL IMPEDANCE**

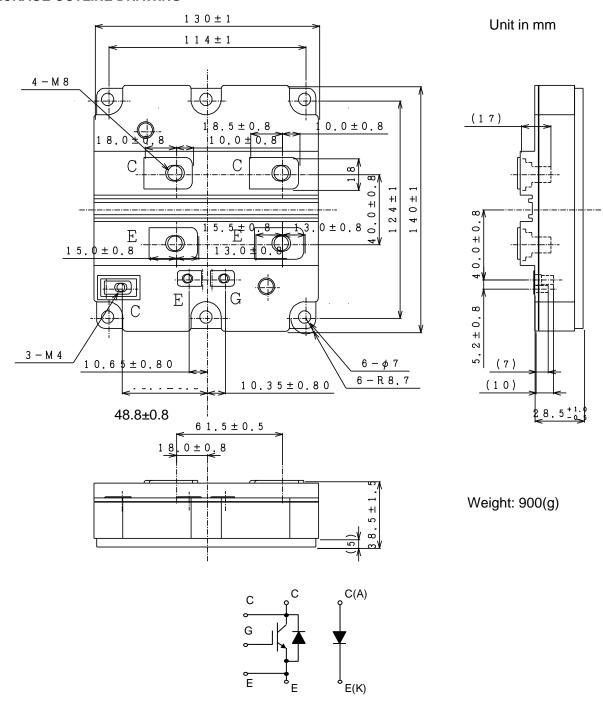


Transient Thermal Impedance Curve

Curve approximation model  $Zth = \Sigma rth[n]*(1-exp(-t/\tau th[n]))$ 

n	1	2	3	4	Unit
τ th[n]	1.45E-01	2.03E-02	2.33E-03	3.16E-04	sec
rth[n,lGBT]	1.41E-02	3.76E-03	3.74E-03	4.21E-04	K/W
rth[n,Diode]	2.10E-02	5.93E-03	5.45E-03	6.50E-04	K/W

#### 7. PACKAGE OUTLINE DRAWING



Circuit diagram

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